

SCOPE: **100mA CMOS SWITCHED-CAPACITOR VOLTAGE CONVERTER 1.5V TO 8V**

<u>Device Type</u>	<u>Generic Number</u>
01	MAX665M(x)/883B

Case Outline(s). The case outlines shall be designated in Mil-Std-1835 and as follows:

<u>Outline Letter</u>	<u>Mil-Std-1835</u>	<u>Case Outline</u>	<u>Package Code</u>
JA	GDIP1-T8 or CDIP2-T8	8 LEAD CERDIP	J8

Absolute Maximum Ratings

Supply Voltage (V^+ to GND, or GND to OUT)	+8.5V
LV Input Voltage	OUT -0.3V to V^+ +0.3V
FC and OSC Input Voltages (the least negative of OUT -0.3V or V^+ -6V) to V^+ +0.3V	
OUT and V^+ Continuous Output Current	120mA
Output Short-circuit Duration to GND <u>1</u> /	1 sec
Lead Temperature (soldering, 10 seconds)	+300°C
Storage Temperature	-65°C to +160°C
Continuous Power Dissipation	$T_A = +70^\circ\text{C}$
8 lead CERDIP (derate 8.0mW/°C above +70°C)	640mW
Junction Temperature, T_J	+150°C
Thermal Resistance, Junction to Case, θ_{JC} :	55°C/W
Thermal Resistance, Junction to Ambient, θ_{JA} :	125°C/W

Recommended Operating Conditions.

Ambient Operating Range (T_A)	-55°C to +125°C
Inverter mode V^+ to GND	+1.5V dc to +8.0V dc
Doubler mode GND to V_{OUT}	+2.5V dc to +8.0V dc

NOTE 1: OUT may be shorted to GND for 1 sec without damage only if the input supply is limited to less than 200mA, but shorting OUT to V^+ may damage the device and should be avoided. Also, for temperatures above +85°C, OUT must not be shorted to GND or V^+ , even instantaneously, or device damage may result.

Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TABLE 1 ELECTRICAL TESTS

PARAMETER	Symbol	CONDITIONS -55 °C ≤ T _A ≤ +125 °C 2/ V ⁺ =5V, C1, C2=150μF, FC=open Unless otherwise specified	Group A Subgroup	Device type	Limits Min	Limits Max	Units
Operating Supply Voltage		R _L =1kΩ, Inverter, LV=open R _L =1kΩ, Inverter, LV=GND R _L =1kΩ, Doubler, LV=OUT	1,2,3	01	3.0 1.5 2.5	8.0 8.0 8.0	V
Supply Current		No Load, FC=open No Load, FC=V ⁺	1,2,3	01		0.5 3.0	mA
Output Current		OUT more negative than -4V OUT more negative than -3.8V	1,3 2	01	100		mA
Output Resistance NOTE 3		I _L =100mA	1,3 2	01		10 12	Ω
Power Efficiency		R _L =1kΩ connected between V ⁺ and OUT R _L =500Ω connected between OUT and GND	1,2,3 1,2,3	01	96 92		%
Voltage Conversion Efficiency		No Load	1,2,3	01	99		%
Power Efficiency		I _L =100mA to GND NOTE 4	TYPICAL	01	88		%
Oscillator Frequency		FC=open NOTE 4 FC=V ⁺ NOTE 4	TYPICAL	01	10 45		kHz
OSC Input Current		FC=open NOTE 4 FC=V ⁺ NOTE 4	TYPICAL	01	±1.1 ±5.0		μA

NOTE 2: In the test circuit, capacitors C1 and C2 are 150μF, 0.2Ω maximum ESR, aluminum electrolytics (Maxim part # MAXC001). Capacitors with higher ESR may reduce output voltage and efficiency.

NOTE 3: Specified output resistance is a combination of internal switch resistance and capacitor ESR.

NOTE 4: Characteristics supplied for use as a typical design limit but not production tested.

		ORDERING INFORMATION
01	J8	MAX665MJA/883B

TERMINAL NUMBER	01
1	FC
2	CAP+
3	GND
4	CAP-
5	OUT
6	LV
7	OSC
8	V ⁺

QUALITY ASSURANCE

Sampling and inspection procedures shall be in accordance with MIL-Prf-38535, Appendix A as specified in Mil-Std-883.

Screening shall be in accordance with Method 5004 of Mil-Std-883. Burn-in test Method 1015:

1. Test Condition, A, B, C, or D.
2. TA = +125°C minimum.
3. Interim and final electrical test requirements shall be specified in Table 2.

Quality conformance inspection shall be in accordance with Method 5005 of Mil-Std-883, including Groups A, B, C, and D inspection.

Group A inspection:

1. Tests as specified in Table 2.
2. Selected subgroups in Table 1, Method 5005 of Mil-Std-883 shall be omitted.

Group C and D inspections:

- a. End-point electrical parameters shall be specified in Table 1.
- b. Steady-state life test, Method 1005 of Mil-Std-883:
 1. Test condition A, B, C, D.
 2. TA = +125°C, minimum.
 3. Test duration, 1000 hours, except as permitted by Method 1005 of Mil-Std-883.

TABLE 2. ELECTRICAL TEST REQUIREMENTS

Mil-Std-883 Test Requirements	Subgroups per Method 5005, Table 1
Interim Electric Parameters Method 5004	1
Final Electrical Parameters Method 5005	1*, 2, 3
Group A Test Requirements Method 5005	1, 2, 3
Group C and D End-Point Electrical Parameters Method 5005	1

* PDA applies to Subgroup 1 only.

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